



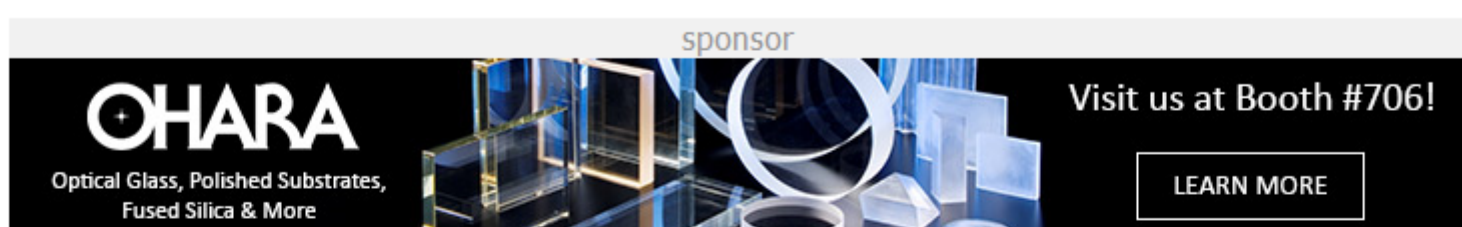
SPIE Optifab 2023



Optifab 2023 to Showcase the Latest in Optical Manufacturing

SPIE Optifab 2023, North America's largest optical manufacturing conference and exhibition, will be held Oct. 16-19 at the Joseph A. Floreano Riverside Convention Center in Rochester, N.Y. The conference will focus on the latest in optical fabrication technologies and will feature expert-led presentations. Attendees will also be able to attend a multiday industry exhibition and courses.

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Featured Exhibitors

[Non-Contact Thickness Measurement](#)

From: Bristol Instruments Inc.

Bristol's Optical Thickness Gauge uses the power of light to make precise, multilayer measurements of transparent and semi-transparent materials. It is ideal for production testing of products such as optical components and lens assemblies, contact and intraocular lenses, displays (OLED, AMOLED, and LCD), medical tubing, balloon catheters, semiconductors, and glass. Bring your sample to the show for on-the-spot measurement or contact us today for a free online demonstration. Visit us at **Booth #607**.



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[Optimize Your Lens Production](#)

From: TRIOPTICS GmbH

Is your objective lens production giving you a headache? Talk to our experts at **Booth #1221**, to learn how we can help improve first pass yields, automate testing, and optimize processes. Book an appointment at info@trioptics-usa.com. TRIOPTICS products set the standard for optical metrology.



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[SK-1300 Fused Silica](#)

From: Ohara Corporation, Western Office

Introducing Ohara's SK-1300 Fused Silica. Ideal for semiconductor equipment, filters, and high-energy laser applications. SK-1300 Fused Silica advantages include extremely low bulk absorption and fluorescence, no laser damage at 1070 nm, high transmission from UV through near-IR, high homogeneity, and low stress birefringence. Blank sizes from 1-inch to 1-meter diameter, and polished substrates 150-, 200-, and 300-mm diameter x 0.5 - 5 mm thick and other custom sizes. Visit us at **Booth #706**.



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[SPS-200 Polisher](#)

From: Satisloh GmbH

Consistent polishing accuracy across a wide range of optical shapes: spheres, aspheres, and freeform surfaces within a working range of 5 - 200 mm, but also a spectrum of other optical surfaces such as cylinders, toroids, and more. It not only offers polishing in Synchrospeed and Variospeed mode, but adaptive deterministic pre- and corrective polishing technology (ADAPT) to achieve highly accurate yet efficiently produced aspheres and freeforms. Visit us at **Booth #521**.



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[Auto Centering Machine with Robot](#)

From: Mildex Inc.

Model SPCM-M1-AT50 Automated Lens Centering Machine with integrated Robot can edge and bevel lenses or windows in a fully automated cycle including loading and unloading of the workpieces. Two integrated work holding pallets can be loaded with hundreds of parts to be processed without further operator intervention. Once processing parameters are set by the operator, the machine can run uninterrupted for 4 - 8 hours. Visit us at **Booth #613**.



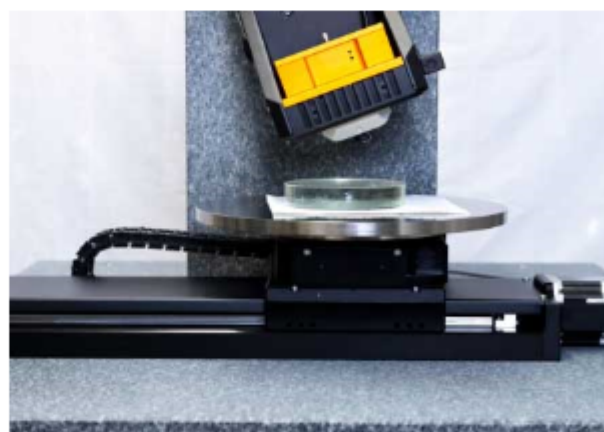
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[Picometer Roughness Measurements](#)

From: Nanosurf AG

Picometer Roughness Measurements on Large Curved Samples — Nanosurf's solutions go beyond the typical metrology tools. For large, heavy, curved samples, determining critical dimensions and roughness can be a challenge. For Nanosurf's atomic force microscope solutions, sample dimensions, weight, and size are not a limiting factor. Visit Nanosurf at **Booth #1110** at this year's Optifab to discover new solutions to your metrology challenges and discuss your applications. Visit website: <https://hubs.la/Q023vXxj0>. Request info: <https://hubs.la/Q023vXvk0>



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[Industrial Laser Monitoring System](#)

From: DataRay Inc.

DataRay's Industrial Laser Monitoring System (ILMS) is specially designed for profiling focused, high-power industrial lasers. It combines reimaging/magnification optics, a polarization preserving beam sampler, and a DataRay beam profiler to measure small beam waists which would otherwise damage a traditional profiler. Magnification of the focused beam allows full pixel-by-pixel 2D measurements of beam spots as small as a few microns; software ensures results do not require post processing or corrections. Visit us at **Booth #172**.



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